

Registration fees

Add 19,6% (VAT) for EC citizen

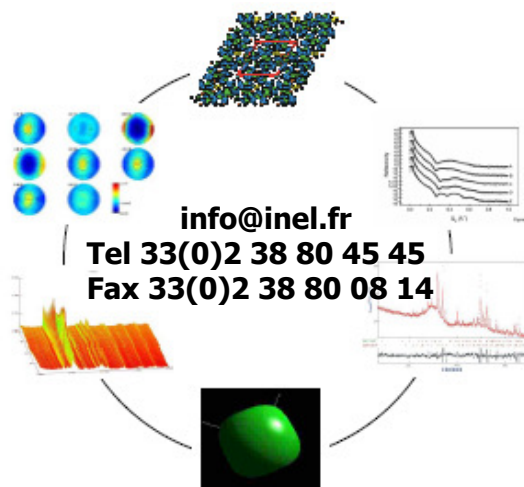
In order to ensure and encourage individual interaction the number of participants will be limited to 40.

Registration fees include :

- Admission and participation to the course
- Coffee breaks, lunches, reception and two conferences dinner

Participants will be required to make their own accommodation and travelling arrangements to and from workshop venue. Organizers will send an hotels list and an access map of the training place. Upon request organizers can make accommodation bookings for participants.

Please direct questions or registration to INEL:



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inel

X-ray diffraction for the
21st Century

WORKSHOP

Combined Analysis Using X-ray and Neutron Scattering

July 4–8, 2011

Caen (France)

5 days training on the
aspect of Combined
Analysis by X-ray and
Neutron Scattering and
introduction to MAUD
software

Aim of the workshop

Is to allow students, academic and non-academic researchers to obtain information relating to the characterisation, structure, microstructure, phase, texture, stress and reflectivity by " Combined Analysis using X-ray and neutron scattering techniques" and relating to a number of samples and structures including : thin films bulk materials, materials with anisotropic crystal structures, polyphased materials, nanomaterials, multi-detectors, etc.

Each type of analysis will be considered individually and then integrated into a combined analysis program. Some specific examples will be studied using X-ray and neutron experimental data.

The objective is to bring together participant's from various fields and to provide an opportunity to discuss individual